## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination YEO ET AL. | Examiner | Art Unit | Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,667,502 B1	12-2003	Agarwal et al.	257/296
	В	US-6,563,190 B1	05-2003	Lee et al.	257/532
-	C	US-5,330,614	07-1994	Ahn, Ji-hong	438/396
	٥	US-5,824,592 A	10-1998	Tseng, Horng-Huei	438/396
	Ε	US-5,946,571 A	08-1999	Hsue et al.	438/255
	F	US-6,303,956 B1	10-2001	Sandhu et al.	257/306
	G	US-6,025,246 A	02-2000	Kim, Tae-sung	438/396
	Н	US-2003/0227044 A1	12-2003	Park, Je-Min	257/301
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.